

165-Bump FP-BGA Commercial Temp Industrial Temp

2M x 18, 1M x 32, 1M x 36 36Mb Sync Burst SRAMs

250 MHz-133 MHz 2.5 V or 3.3 V V_{DD} 2.5 V or 3.3 V I/O

Features

- IEEE 1149.1 JTAG-compatible Boundary Scan
- 2.5 V or 3.3 V +10%/-10% core power supply
- 2.5 V or 3.3 V I/O supply
- LBO pin for Linear or Interleaved Burst mode
- Internal input resistors on mode pins allow floating mode pins
- Byte Write (\overline{BW}) and/or Global Write (\overline{GW}) operation
- Internal self-timed write cycle
- Automatic power-down for portable applications
- JEDEC-standard 165-bump FP-BGA package
- RoHS-compliant 165-bump BGA package available

Functional Description

Applications

The GS832118/32/36E is a 37,748,736-bit high performance synchronous SRAM with a 2-bit burst address counter. Although of a type originally developed for Level 2 Cache applications supporting high performance CPUs, the device now finds application in synchronous SRAM applications, ranging from DSP main store to networking chip set support.

Controls

Addresses, data I/Os, chip enable $(\overline{E1})$, address burst control inputs $(\overline{ADSP}, \overline{ADSC}, \overline{ADV})$ and write control inputs $(\overline{Bx}, \overline{BW}, \overline{GW})$ are synchronous and are controlled by a positive-edge-triggered clock input (CK). Output enable (\overline{G}) and power down control (ZZ) are asynchronous inputs. Burst cycles can be initiated with either \overline{ADSP} or \overline{ADSC} inputs. In Burst mode, subsequent burst addresses are generated internally and are controlled by \overline{ADV} . The burst address counter may be configured to count in either linear or interleave order with the Linear Burst Order (\overline{LBO}) input. The Burst function need not be used. New addresses can be loaded on every cycle with no degradation of chip performance.

Flow Through/Pipeline Reads

The function of the Data Output register can be controlled by the user via the \overline{FT} mode pin (Pin 14). Holding the \overline{FT} mode pin low places the RAM in Flow Through mode, causing output data to bypass the Data Output Register. Holding \overline{FT} high places the RAM in Pipeline mode, activating the rising-edge-triggered Data Output Register.

SCD Pipelined Reads

The GS832118/32/36E is a SCD (Single Cycle Deselect) pipelined synchronous SRAM. DCD (Dual Cycle Deselect) versions are also available. SCD SRAMs pipeline deselect commands one stage less than read commands. SCD RAMs begin turning off their outputs immediately after the deselect command has been captured in the input registers.

Byte Write and Global Write

Byte write operation is performed by using Byte Write enable (\overline{BW}) input combined with one or more individual byte write signals (\overline{Bx}) . In addition, Global Write (\overline{GW}) is available for writing all bytes at one time, regardless of the Byte Write control inputs.

Sleep Mode

Low power (Sleep mode) is attained through the assertion (High) of the ZZ signal, or by stopping the clock (CK). Memory data is retained during Sleep mode.

Core and Interface Voltages

The GS832118/32/36E operates on a 2.5 V or 3.3 V power supply. All input are 3.3 V and 2.5 V compatible. Separate output power (V_{DDQ}) pins are used to decouple output noise from the internal circuits and are 3.3 V and 2.5 V compatible.

Parameter Synopsis

		-250	-225	-200	-166	-150	-133	Unit
	t _{KQ}	2.5	2.7	3.0	3.5	3.8	4.0	ns
Pipeline	tCycle	4.0	4.4	5.0	6.0	6.6	7.5	ns
3-1-1-1	Curr (x18)	285	265	245	220	210	185	mΑ
	Curr (x32/x36)	350	320	295	260	240	215	mA
Flow	t _{KQ}	6.5	7.0	7.5	8.0	8.5	8.5	ns
Through	tCycle	6.5	7.0	7.5	8.0	8.5	8.5	ns
2-1-1-1	Curr (x18)	205	195	185	175	165	155	mA
	Curr (x32/x36)	235	225	210	200	190	175	mA



165 Bump BGA—x18 Commom I/O—Top View (Package E)

	1	2	3	4	5	6	7	8	9	10	11	
Α	NC	Α	E1	BB	NC	E3	BW	ADSC	ADV	Α	А	Α
В	NC	Α	E2	NC	BA	CK	GW	G	ADSP	Α	NC	В
С	NC	NC	V_{DDQ}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DDQ}	NC	DQPA	С
D	NC	DQB	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	NC	DQA	D
Е	NC	DQB	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	NC	DQA	Е
F	NC	DQB	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	NC	DQA	F
G	NC	DQB	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	NC	DQA	G
Н	FT	MCL	NC	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	NC	NC	ZZ	Н
J	DQB	NC	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	NC	J
K	DQB	NC	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	NC	K
L	DQB	NC	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	NC	L
M	DQB	NC	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	NC	М
N	DQPB	NC	V_{DDQ}	V_{SS}	NC	Α	NC	V_{SS}	V_{DDQ}	NC	NC	N
Р	NC	NC	Α	Α	TDI	A1	TDO	Α	Α	Α	Α	Р
R	LBO	A19	Α	Α	TMS	A0	TCK	Α	Α	Α	Α	R

11 x 15 Bump BGA—15 mm x 17 mm Body—1.0 mm Bump Pitch



165 Bump BGA—x32 Common I/O—Top View (Package E)

	1	2	3	4	5	6	7	8	9	10	11	
Α	NC	Α	E1	BC	BB	E3	BW	ADSC	ADV	Α	NC	А
В	NC	Α	E2	BD	BA	CK	GW	G	ADSP	Α	NC	В
С	NC	NC	V_{DDQ}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DDQ}	NC	NC	С
D	DQC	DQC	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQB	DQB	D
E	DQC	DQC	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQB	DQB	Е
F	DQC	DQC	$V_{\rm DDQ}$	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQB	DQB	F
G	DQC	DQC	$V_{\rm DDQ}$	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQB	DQB	G
Н	FT	MCL	NC	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	NC	NC	ZZ	Н
J	DQD	DQD	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	DQA	J
K	DQD	DQD	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	DQA	K
L	DQD	DQD	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	DQA	L
M	DQD	DQD	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	DQA	М
N	NC	NC	V_{DDQ}	V_{SS}	NC	Α	NC	V_{SS}	V_{DDQ}	NC	NC	N
Р	NC	NC	Α	Α	TDI	A1	TDO	Α	Α	Α	Α	Р
R	LBO	Α	Α	Α	TMS	A0	TCK	Α	Α	Α	Α	R

11 x 15 Bump BGA—15 mm x 17 mm Body—1.0 mm Bump Pitch



165 Bump BGA—x36 Common I/O—Top View (Package E)

	1	2	3	4	5	6	7	8	9	10	11	
Α	NC	Α	E1	BC	BB	E3	BW	ADSC	ADV	Α	NC	Α
В	NC	Α	E2	BD	BA	СК	GW	G	ADSP	Α	NC	В
С	DQPC	NC	V_{DDQ}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DDQ}	NC	DQPB	С
D	DQC	DQC	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQB	DQB	D
E	DQC	DQC	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQB	DQB	Е
F	DQC	DQC	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQB	DQB	F
G	DQC	DQC	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQB	DQB	G
Н	FT	MCL	NC	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	NC	NC	ZZ	Н
J	DQD	DQD	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	DQA	J
K	DQD	DQD	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	DQA	K
L	DQD	DQD	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	DQA	L
M	DQD	DQD	V_{DDQ}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQ}	DQA	DQA	М
N	DQPD	NC	V_{DDQ}	V_{SS}	NC	Α	NC	V_{SS}	V_{DDQ}	NC	DQPA	N
Р	NC	NC	Α	Α	TDI	A1	TDO	Α	Α	Α	Α	Р
R	LBO	Α	Α	Α	TMS	A0	TCK	Α	Α	Α	Α	R

11 x 15 Bump BGA—15 mm x 17 mm Body—1.0 mm Bump Pitch

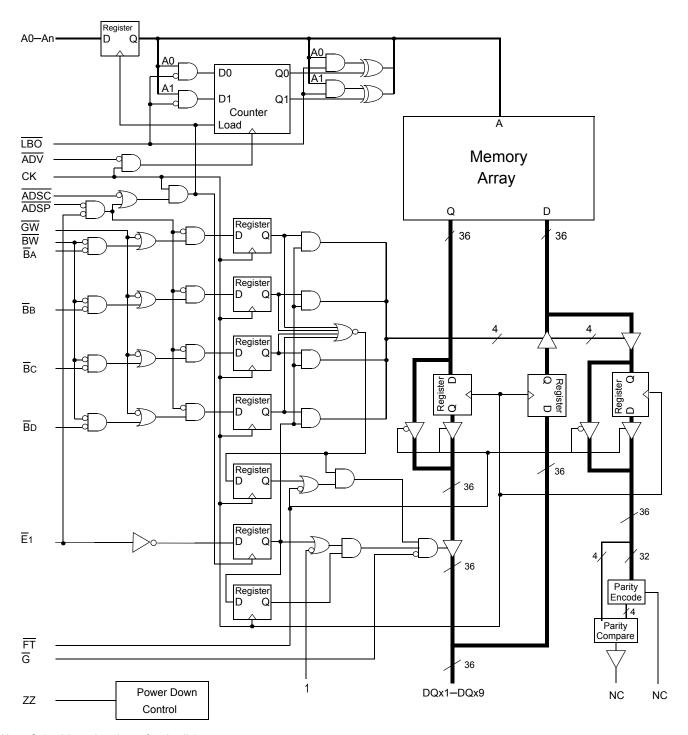


GS832118/32/36E 165-Bump BGA Pin Description

Symbol	Туре	Description
A0, A1	ı	Address field LSBs and Address Counter Preset Inputs
А	I	Address Inputs
DQA DQB DQc DQD	1/0	Data Input and Output pins
Ba, Bb, Bc, Bd	I	Byte Write Enable for DQA, DQB, DQc, DQD I/Os; active low
NC	_	No Connect
CK	I	Clock Input Signal; active high
BW	I	Byte Write—Writes all enabled bytes; active low
GW	I	Global Write Enable—Writes all bytes; active low
E ₁	I	Chip Enable; active low
<u>E</u> 3	I	Chip Enable; active low
E ₂	I	Chip Enable; active high
G	I	Output Enable; active low
ADV	I	Burst address counter advance enable; active I0w
ADSC, ADSP	I	Address Strobe (Processor, Cache Controller); active low
ZZ	I	Sleep mode control; active high
FT	I	Flow Through or Pipeline mode; active low
LBO	I	Linear Burst Order mode; active low
TMS	I	Scan Test Mode Select
TDI	I	Scan Test Data In
TDO	0	Scan Test Data Out
TCK	I	Scan Test Clock
MCL	_	Must Connect Low
V _{DD}	I	Core power supply
V _{SS}	I	I/O and Core Ground
V_{DDQ}	I	Output driver power supply



GS832118/32/36 Block Diagram



Note: Only x36 version shown for simplicity.



Mode Pin Functions

Mode Name	Pin Name State		Function
Burst Order Control	LBO	L	Linear Burst
Buist Order Control	LDO	Н	Interleaved Burst
Output Register Control	FT	L	Flow Through
Output Negister Control	ГІ	H or NC	Pipeline
Dower Down Control	77	L or NC	Active
Power Down Control	ZZ	Н	Standby, I _{DD} = I _{SB}

Note

There are pull-up devices on the \overline{FT} pin and a pull-down device on the ZZ pin, so those input pins can be unconnected and the chip will operate in the default states as specified in the above tables.

Burst Counter Sequences

Linear Burst Sequence

	A[1:0]	A[1:0]	A[1:0]	A[1:0]
1st address	00	01	10	11
2nd address	01	10	11	00
3rd address	10	11	00	01
4th address	11	00	01	10

Note:

The burst counter wraps to initial state on the 5th clock.

Interleaved Burst Sequence

	A[1:0]	A[1:0]	A[1:0]	A[1:0]
1st address	00	01	10	11
2nd address	01	00	11	10
3rd address	10	11	00	01
4th address	11	10	01	00

Note:

The burst counter wraps to initial state on the 5th clock.

BPR 1999.05.18



Byte Write Truth Table

Function	GW	BW	Ba	Вв	Bc	BD	Notes
Read	Н	Н	Х	Х	Х	Х	1
Write No Bytes	Н	L	Н	Н	Н	Н	1
Write byte a	Н	L	L	Н	Н	Н	2, 3
Write byte b	Н	L	Н	L	Н	Н	2, 3
Write byte c	Н	L	Н	Н	L	Н	2, 3, 4
Write byte d	Н	L	Н	Н	Н	L	2, 3, 4
Write all bytes	Н	L	L	L	L	L	2, 3, 4
Write all bytes	L	Х	Х	Х	Х	Х	

- 1. All byte outputs are active in read cycles regardless of the state of Byte Write Enable inputs, \overline{BA} , \overline{BB} , \overline{BC} and/or \overline{BD} .
- 2. Byte Write Enable inputs \overline{BA} , \overline{BB} , \overline{BC} and/or \overline{BD} may be used in any combination with \overline{BW} to write single or multiple bytes.
- 3. All byte I/Os remain High-Z during all write operations regardless of the state of Byte Write Enable inputs.
- 4. Bytes "C" and "D" are only available on the x32 and x36 versions.



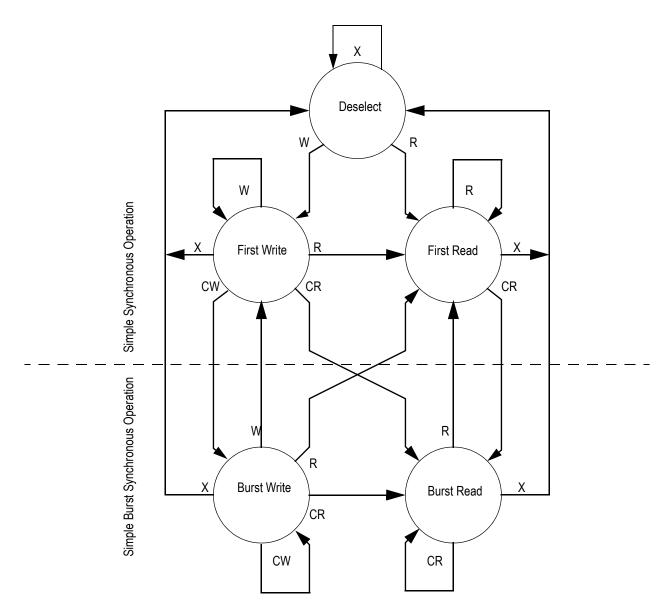
Synchronous Truth Table

Operation	Address Used	State Diagram Key	Ē1	E2	E ₃	ADSP	ADSC	ADV	w	DQ ³
Deselect Cycle, Power Down	None	Х	L	Х	Н	Х	L	Х	Х	High-Z
Deselect Cycle, Power Down	None	Х	Ы	L	X	X	L	X	X	High-Z
Deselect Cycle, Power Down	None	Х	L	Х	Н	L	Х	Х	Х	High-Z
Deselect Cycle, Power Down	None	Х	L	L	Х	L	Х	Х	Х	High-Z
Deselect Cycle, Power Down	None	Х	Н	Х	Х	Х	L	X	Х	High-Z
Read Cycle, Begin Burst	External	R	L	Н	L	L	Х	Х	Х	Q
Read Cycle, Begin Burst	External	R	L	Н	L	Н	L	X	F	Q
Write Cycle, Begin Burst	External	W	L	Н	L	Н	L	Х	T	D
Read Cycle, Continue Burst	Next	CR	Χ	Χ	Χ	Н	Н	L	F	Q
Read Cycle, Continue Burst	Next	CR	Н	Х	Х	Х	Н	L	F	Q
Write Cycle, Continue Burst	Next	CW	Χ	Χ	Χ	Н	Н	L	Т	D
Write Cycle, Continue Burst	Next	CW	Н	Χ	Χ	Χ	Н	L	T	D
Read Cycle, Suspend Burst	Current		Χ	Х	Χ	Н	Н	Н	F	Q
Read Cycle, Suspend Burst	Current		Н	Х	Χ	Х	Н	Н	F	Q
Write Cycle, Suspend Burst	Current		Χ	Х	Χ	Н	Н	Н	Т	D
Write Cycle, Suspend Burst	Current		Н	Х	Х	Х	Н	Н	Т	D

- 1. X = Don't Care, H = High, L = Low
- 2. E = T (True) if $E_2 = 1$ and $\overline{E}_1 = \overline{E}_3 = 0$; E = F (False) if $E_2 = 0$ or $\overline{E}_1 = 1$ or $\overline{E}_3 = 1$
- 3. W = T (True) and F (False) is defined in the Byte Write Truth Table preceding.
- 4. \overline{G} is an asynchronous input. \overline{G} can be driven high at any time to disable active output drivers. \overline{G} low can only enable active drivers (shown as "Q" in the Truth Table above).
- 5. All input combinations shown above are tested and supported. Input combinations shown in gray boxes need not be used to accomplish basic synchronous or synchronous burst operations and may be avoided for simplicity.
- 6. Tying ADSP high and ADSC low allows simple non-burst synchronous operations. See **BOLD** items above.
- 7. Tying ADSP high and ADV low while using ADSC to load new addresses allows simple burst operations. See ITALIC items above.



Simplified State Diagram



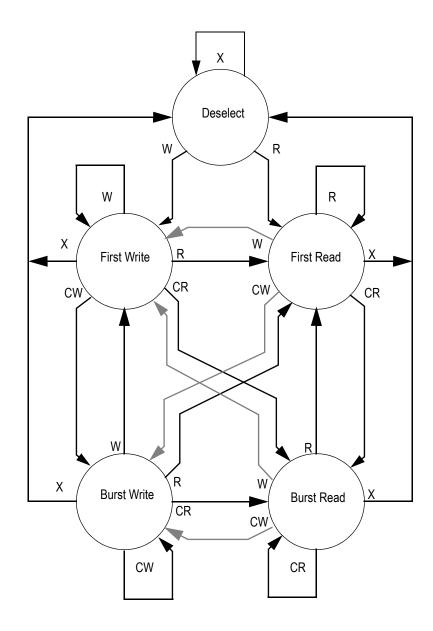
Notes:

- The diagram shows only supported (tested) synchronous state transitions. The diagram $\underline{\text{presumes }\overline{G}\text{ is }\underline{\text{tied}}\text{ low}}$. The $\underline{\text{upper portion of the diagram}}$ assumes active use of only the Enable ($\overline{\text{E1}}$) and Write ($\overline{\text{BA}}$, $\overline{\text{BB}}$, $\overline{\text{BC}}$, $\overline{\text{BD}}$, $\overline{\text{BW}}$, and $\overline{\text{GW}}$) control inputs, and that ADSP is tied high and ADSC is tied low.
- The upper and lower portions of the diagram together assume active use of only the Enable, Write, and ADSC control inputs, and assumes ADSP is tied high and ADV is tied low.

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Simplified State Diagram with \overline{G}



- 1. The diagram shows supported (tested) synchronous state transitions plus supported transitions that depend upon the use of \overline{G} .
- 2. Use of "Dummy Reads" (Read Cycles with \overline{G} High) may be used to make the transition from read cycles to write cycles without passing through a deselect cycle. Dummy read cycles increment the address counter just like normal read cycles.
- 3. Transitions shown in gray tone assume G has been pulsed high long enough to turn the RAM's drivers off and for incoming data to meet Data Input Set Up Time.



Absolute Maximum Ratings

(All voltages reference to $V_{\rm SS}$)

Symbol	Description	Value	Unit
V_{DD}	Voltage on V _{DD} Pins	-0.5 to 4.6	V
V_{DDQ}	Voltage in V _{DDQ} Pins	-0.5 to 4.6	V
V _{I/O}	Voltage on I/O Pins	$-0.5 \text{ to V}_{\text{DDQ}} + 0.5 \ (\leq 4.6 \text{ V max.})$	V
V _{IN}	Voltage on Other Input Pins	$-0.5 \text{ to V}_{DD} + 0.5 \ (\leq 4.6 \text{ V max.})$	V
I _{IN}	Input Current on Any Pin	+/-20	mA
l _{out}	Output Current on Any I/O Pin	+/20	mA
P_{D}	Package Power Dissipation	1.5	W
T _{STG}	Storage Temperature	-55 to 125	°C
T _{BIAS}	Temperature Under Bias	-55 to 125	°C

Note:

Permanent damage to the device may occur if the Absolute Maximum Ratings are exceeded. Operation should be restricted to Recommended Operating Conditions. Exposure to conditions exceeding the Absolute Maximum Ratings, for an extended period of time, may affect reliability of this component.

Power Supply Voltage Ranges

Parameter	Symbol	Min.	Тур.	Max.	Unit	Notes
3.3 V Supply Voltage	V_{DD3}	3.0	3.3	3.6	V	
2.5 V Supply Voltage	V _{DD2}	2.3	2.5	2.7	V	
3.3 V V _{DDQ} I/O Supply Voltage	V_{DDQ3}	3.0	3.3	3.6	V	
2.5 V V _{DDQ} I/O Supply Voltage	V_{DDQ2}	2.3	2.5	2.7	V	

- 1. The part numbers of Industrial Temperature Range versions end the character "I". Unless otherwise noted, all performance specifications quoted are evaluated for worst case in the temperature range marked on the device.
- 2. Input Under/overshoot voltage must be -2 V > Vi < V_{DDn}+2 V not to exceed 4.6 V maximum, with a pulse width not to exceed 20% tKC.



V_{DDQ3} Range Logic Levels

Parameter	Symbol	Min.	Тур.	Max.	Unit	Notes
V _{DD} Input High Voltage	V _{IH}	2.0	_	V _{DD} + 0.3	V	1
V _{DD} Input Low Voltage	V _{IL}	-0.3	_	0.8	V	1
V _{DDQ} I/O Input High Voltage	V _{IHQ}	2.0	_	V _{DDQ} + 0.3	V	1,3
V _{DDQ} I/O Input Low Voltage	V _{ILQ}	-0.3	_	0.8	V	1,3

Notes:

- 1. The part numbers of Industrial Temperature Range versions end the character "I". Unless otherwise noted, all performance specifications quoted are evaluated for worst case in the temperature range marked on the device.
- 2. Input Under/overshoot voltage must be -2 V > Vi < V_{DDn}+2 V not to exceed 4.6 V maximum, with a pulse width not to exceed 20% tKC.
- 3. V_{IHO} (max) is voltage on V_{DDO} pins plus 0.3 V.

V_{DDQ2} Range Logic Levels

Parameter	Symbol	Min.	Тур.	Max.	Unit	Notes
V _{DD} Input High Voltage	V _{IH}	0.6*V _{DD}	_	V _{DD} + 0.3	V	1
V _{DD} Input Low Voltage	V _{IL}	-0.3	_	0.3*V _{DD}	V	1
V _{DDQ} I/O Input High Voltage	V _{IHQ}	0.6*V _{DD}	_	V _{DDQ} + 0.3	V	1,3
V _{DDQ} I/O Input Low Voltage	V _{ILQ}	-0.3	_	0.3*V _{DD}	V	1,3

Notes:

- 1. The part numbers of Industrial Temperature Range versions end the character "I". Unless otherwise noted, all performance specifications quoted are evaluated for worst case in the temperature range marked on the device.
- 2. Input Under/overshoot voltage must be −2 V > Vi < V_{DDn}+2 V not to exceed 4.6 V maximum, with a pulse width not to exceed 20% tKC.
- 3. V_{IHQ} (max) is voltage on V_{DDQ} pins plus 0.3 V.

Recommended Operating Temperatures

Parameter	Symbol	Min.	Тур.	Max.	Unit	Notes
Ambient Temperature (Commercial Range Versions)	T _A	0	25	70	°C	2
Ambient Temperature (Industrial Range Versions)	T _A	– 40	25	85	°C	2

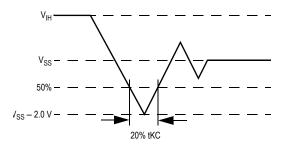
Notes:

- The part numbers of Industrial Temperature Range versions end the character "I". Unless otherwise noted, all performance specifications quoted are evaluated for worst case in the temperature range marked on the device.
- 2. Input Under/overshoot voltage must be −2 V > Vi < V_{DDn}+2 V not to exceed 4.6 V maximum, with a pulse width not to exceed 20% tKC.

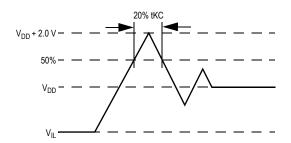
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Undershoot Measurement and Timing



Overshoot Measurement and Timing



Capacitance

$$(T_A = 25^{\circ}C, f = 1 \text{ MHz}, V_{DD} = 2.5 \text{ V})$$

Parameter	Symbol	Test conditions	Тур.	Max.	Unit
Input Capacitance	C _{IN}	V _{IN} = 0 V	4	5	pF
Input/Output Capacitance	C _{I/O}	V _{OUT} = 0 V	6	7	pF

Note:

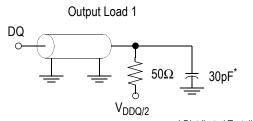
These parameters are sample tested.

AC Test Conditions

Parameter	Conditions
Input high level	V _{DD} – 0.2 V
Input low level	0.2 V
Input slew rate	1 V/ns
Input reference level	V _{DDQ} /2
Output reference level	V _{DDQ} /2
Output load	Fig. 1

Notes:

- 1. Include scope and jig capacitance.
- 2. Test conditions as specified with output loading as shown in **Fig. 1** unless otherwise noted.
- 3. Device is deselected as defined by the Truth Table.



* Distributed Test Jig Capacitance



DC Electrical Characteristics

Parameter	Symbol	Test Conditions	Min	Max
Input Leakage Current (except mode pins)	I _{IL}	V _{IN} = 0 to V _{DD}	–2 uA	2 uA
ZZ Input Current	I _{IN1}	$V_{DD} \ge V_{IN} \ge V_{IH}$ $0 \ V \le V_{IN} \le V_{IH}$	–1 uA –1 uA	1 uA 100 uA
FT, SCD, ZQInput Current	I _{IN2}	$V_{DD} \ge V_{IN} \ge V_{IL}$ $0 \ V \le V_{IN} \le V_{IL}$	–100 uA –1 uA	1 uA 1 uA
Output Leakage Current (x36/x72)	I _{OL}	Output Disable, V _{OUT} = 0 to V _{DD}	–1 uA	1 uA
Output Leakage Current (x18)	I _{OL}	Output Disable, V _{OUT} = 0 to V _{DD}	–1 uA	1 uA
Output High Voltage	V _{OH2}	I _{OH} = -8 mA, V _{DDQ} = 2.375 V	1.7 V	_
Output High Voltage	V _{OH3}	$I_{OH} = -8 \text{ mA}, V_{DDQ} = 3.135 \text{ V}$	2.4 V	_
Output Low Voltage	V _{OL}	I _{OL} = 8 mA	_	0.4 V

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Operating Currents

					-2	50	-2	25	-2	00	-1	66	-1	50	-1		
Parameter	Test Conditions	I	Mode	Symbol	0 to 70°C	-40 to 85°C	Unit										
		(x32/	Pipeline	I _{DD} I _{DDQ}	300 50	320 50	275 45	295 45	255 40	275 40	225 35	245 35	210 30	230 30	190 25	210 25	mA
Operating	Device Selected; All other inputs	x36)	Flow Through	I _{DD} I _{DDQ}	210 25	220 25	200 25	210 25	190 20	200 20	180 20	190 20	170 20	180 20	160 15	170 15	mA
Current	Current $\geq V_{IH}$ or $\leq V_{IL}$ Output open	(x18)	Pipeline	I _{DD} I _{DDQ}	260 25	280 25	240 25	260 25	225 20	245 20	200 20	220 20	190 20	210 20	170 15	190 15	mA
		(X16)	Flow Through	I _{DD} I _{DDQ}	190 15	200 15	180 15	190 15	170 15	180 15	160 15	170 15	150 15	160 15	140 15	150 15	mA
Standby			Pipeline	I _{SB}	60	80	60	80	60	80	60	80	60	80	60	80	mA
Current	$ZZ \ge V_{DD} - 0.2 V$	_	Flow Through	I _{SB}	60	80	60	80	60	80	60	80	60	80	60	80	mA
Deselect	Device Deselected;		Pipeline	I _{DD}	100	115	95	110	90	105	85	100	85	100	80	95	mA
Current	All other inputs $\geq V_{IH}$ or $\leq V_{IL}$	_	Flow Through	I _{DD}	85	100	85	100	80	95	80	95	75	90	70	85	mA

Notes

- 1. I_{DD} and I_{DDQ} apply to any combination of V_{DD3} , V_{DD2} , V_{DDQ3} , and V_{DDQ2} operation.
- 2. All parameters listed are worst case scenario.



GS832118/32/36E-250/225/200/166/150/133



AC Electrical Characteristics

	Parameter	Symbol	-25	50	-22	25	-20	00	-16	66	-1	50	-1	33	Unit
	raiailletei	Syllibol	Min	Max	Oille										
	Clock Cycle Time	tKC	4.0	_	4.4	_	5.0	_	6.0	_	6.7	_	7.5	_	ns
	Clock to Output Valid	tKQ	_	2.5	_	2.7	_	3.0	_	3.4	_	3.8	_	4.0	ns
Dineline	Clock to Output Invalid	tKQX	1.5		1.5		1.5	_	1.5	_	1.5	_	1.5	_	ns
Pipeline	Clock to Output in Low-Z	tLZ ¹	1.5	_	1.5	_	1.5	_	1.5	_	1.5	_	1.5	_	ns
	Setup time	tS	1.2	_	1.3	_	1.4	_	1.5	_	1.5	_	1.5	_	ns
	Hold time	tH	0.2	_	0.3	_	0.4	_	0.5	_	0.5	_	0.5	_	ns
	Clock Cycle Time	tKC	6.5	_	7.0	_	7.5	_	8.0	_	8.5	_	8.5	_	ns
	Clock to Output Valid	tKQ	_	6.5	_	7.0	_	7.5	_	8.0	_	8.5	_	8.5	ns
Flow	Clock to Output Invalid	tKQX	3.0	_	3.0	_	3.0	_	3.0	_	3.0	_	3.0	_	ns
Through	Clock to Output in Low-Z	tLZ ¹	3.0		3.0		3.0	_	3.0	_	3.0	_	3.0	_	ns
	Setup time	tS	1.5	_	1.5	_	1.5	_	1.5	_	1.5	_	1.5	_	ns
	Hold time	tH	0.5	_	0.5	_	0.5	_	0.5	_	0.5	_	0.5	_	ns
	Clock HIGH Time	tKH	1.3	_	1.3	_	1.3	_	1.3	_	1.5	_	1.7	_	ns
	Clock LOW Time	tKL	1.5	_	1.5	_	1.5	_	1.5	_	1.7	_	2	_	ns
	Clock to Output in High-Z	tHZ ¹	1.5	2.5	1.5	2.7	1.5	3.0	1.5	3.0	1.5	3.0	1.5	3.0	ns
	G to Output Valid	tOE	_	2.5	_	2.7	_	3.0	_	3.5	_	3.8	_	4.0	ns
	G to output in Low-Z	tOLZ ¹	0	_	0	_	0	_	0	_	0	_	0	_	ns
	G to output in High-Z	tOHZ ¹	_	2.5	_	2.7	_	3.0	_	3.0	_	3.0	_	3.0	ns
	ZZ setup time	tZZS ²	5	_	5	_	5	_	5	_	5	_	5	_	ns
	ZZ hold time	tZZH ²	1	_	1	_	1	_	1	_	1	_	1	_	ns
	ZZ recovery	tZZR	20	_	20	_	20	_	20		20		20		ns

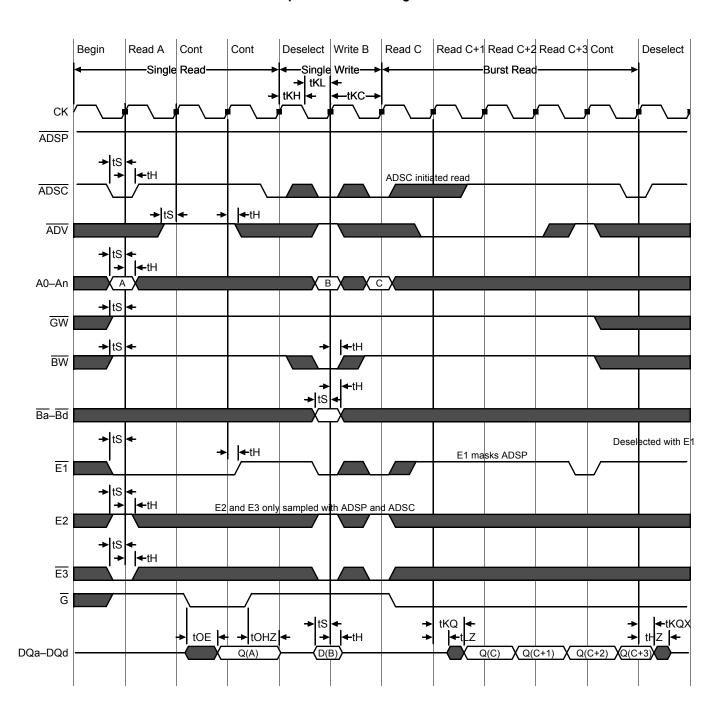
Notes:

- 1. These parameters are sampled and are not 100% tested
- 2. ZZ is an asynchronous signal. However, In order to be recognized on any given clock cycle, ZZ must meet the specified setup and hold times as specified above.

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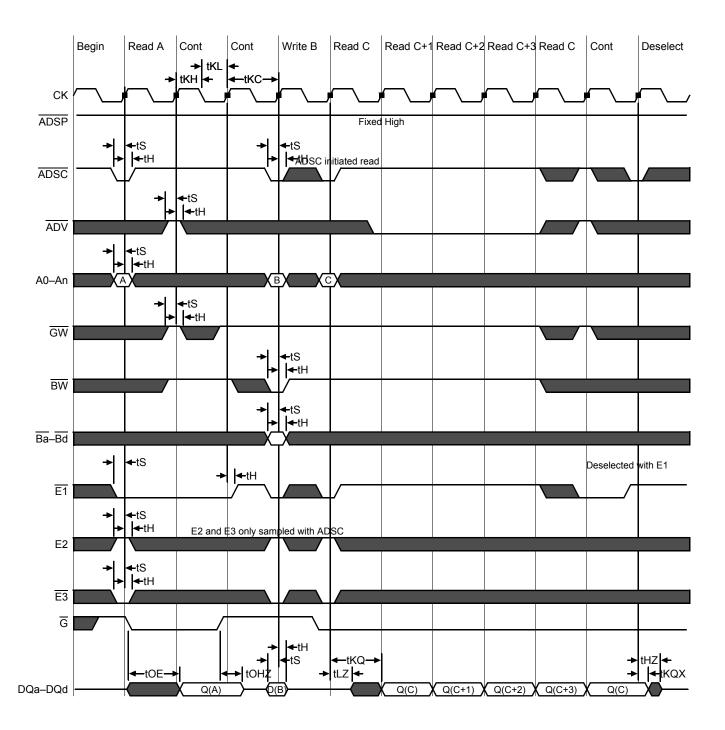


Pipeline Mode Timing





Flow Through Mode Timing



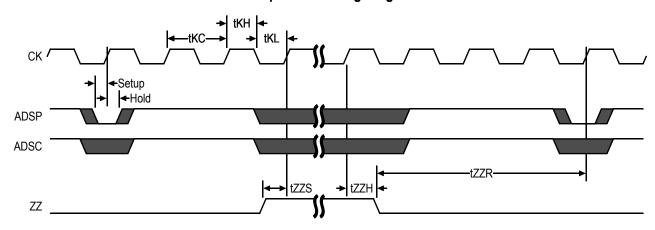


Sleep Mode

During normal operation, ZZ must be pulled low, either by the user or by its internal pull down resistor. When ZZ is pulled high, the SRAM will enter a Power Sleep mode after 2 cycles. At this time, internal state of the SRAM is preserved. When ZZ returns to low, the SRAM operates normally after ZZ recovery time.

Sleep mode is a low current, power-down mode in which the device is deselected and current is reduced to $I_{SB}2$. The duration of Sleep mode is dictated by the length of time the ZZ is in a High state. After entering Sleep mode, all inputs except ZZ become disabled and all outputs go to High-Z The ZZ pin is an asynchronous, active high input that causes the device to enter Sleep mode. When the ZZ pin is driven high, $I_{SB}2$ is guaranteed after the time tZZI is met. Because ZZ is an asynchronous input, pending operations or operations in progress may not be properly completed if ZZ is asserted. Therefore, Sleep mode must not be initiated until valid pending operations are completed. Similarly, when exiting Sleep mode during tZZR, only a Deselect or Read commands may be applied while the SRAM is recovering from Sleep mode.

Sleep Mode Timing Diagram



Application Tips

Single and Dual Cycle Deselect

SCD devices (like this one) force the use of "dummy read cycles" (read cycles that are launched normally but that are ended with the output drivers inactive) in a fully synchronous environment. Dummy read cycles waste performance but their use usually assures there will be no bus contention in transitions from reads to writes or between banks of RAMs. DCD SRAMs do not waste bandwidth on dummy cycles and are logically simpler to manage in a multiple bank application (wait states need not be inserted at bank address boundary crossings) but greater care must be exercised to avoid excessive bus contention.

JTAG Port Operation

Overview

The JTAG Port on this RAM operates in a manner that is compliant with IEEE Standard 1149.1-1990, a serial boundary scan interface standard (commonly referred to as JTAG). The JTAG Port input interface levels scale with V_{DD} . The JTAG output drivers are powered by V_{DDO} .

Disabling the JTAG Port

It is possible to use this device without utilizing the JTAG port. The port is reset at power-up and will remain inactive unless clocked. TCK, TDI, and TMS are designed with internal pull-up circuits. To assure normal operation of the RAM with the JTAG Port unused, TCK, TDI, and TMS may be left floating or tied to either V_{DD} or V_{SS} . TDO should be left unconnected.



JTAG Pin Descriptions

Pin	Pin Name	I/O	Description
TCK	Test Clock	In	Clocks all TAP events. All inputs are captured on the rising edge of TCK and all outputs propagate from the falling edge of TCK.
TMS	Test Mode Select	In	The TMS input is sampled on the rising edge of TCK. This is the command input for the TAP controller state machine. An undriven TMS input will produce the same result as a logic one input level.
TDI	Test Data In	In	The TDI input is sampled on the rising edge of TCK. This is the input side of the serial registers placed between TDI and TDO. The register placed between TDI and TDO is determined by the state of the TAP Controller state machine and the instruction that is currently loaded in the TAP Instruction Register (refer to the TAP Controller State Diagram). An undriven TDI pin will produce the same result as a logic one input level.
TDO	Test Data Out	Out	Output that is active depending on the state of the TAP state machine. Output changes in response to the falling edge of TCK. This is the output side of the serial registers placed between TDI and TDO.

Note:

This device does not have a TRST (TAP Reset) pin. TRST is optional in IEEE 1149.1. The Test-Logic-Reset state is entered while TMS is held high for five rising edges of TCK. The TAP Controller is also reset automaticly at power-up.

JTAG Port Registers

Overview

The various JTAG registers, refered to as Test Access Port orTAP Registers, are selected (one at a time) via the sequences of 1s and 0s applied to TMS as TCK is strobed. Each of the TAP Registers is a serial shift register that captures serial input data on the rising edge of TCK and pushes serial data out on the next falling edge of TCK. When a register is selected, it is placed between the TDI and TDO pins.

Instruction Register

The Instruction Register holds the instructions that are executed by the TAP controller when it is moved into the Run, Test/Idle, or the various data register states. Instructions are 3 bits long. The Instruction Register can be loaded when it is placed between the TDI and TDO pins. The Instruction Register is automatically preloaded with the IDCODE instruction at power-up or whenever the controller is placed in Test-Logic-Reset state.

Bypass Register

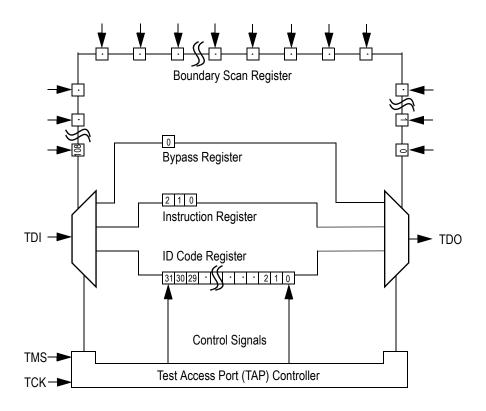
The Bypass Register is a single bit register that can be placed between TDI and TDO. It allows serial test data to be passed through the RAM's JTAG Port to another device in the scan chain with as little delay as possible.

Boundary Scan Register

The Boundary Scan Register is a collection of flip flops that can be preset by the logic level found on the RAM's input or I/O pins. The flip flops are then daisy chained together so the levels found can be shifted serially out of the JTAG Port's TDO pin. The Boundary Scan Register also includes a number of place holder flip flops (always set to a logic 1). The relationship between the device pins and the bits in the Boundary Scan Register is described in the Scan Order Table following. The Boundary Scan Register, under the control of the TAP Controller, is loaded with the contents of the RAMs I/O ring when the controller is in Capture-DR state and then is placed between the TDI and TDO pins when the controller is moved to Shift-DR state. SAMPLE-Z, SAMPLE/PRELOAD and EXTEST instructions can be used to activate the Boundary Scan Register.



JTAG TAP Block Diagram



Identification (ID) Register

The ID Register is a 32-bit register that is loaded with a device and vendor specific 32-bit code when the controller is put in Capture-DR state with the IDCODE command loaded in the Instruction Register. The code is loaded from a 32-bit on-chip ROM. It describes various attributes of the RAM as indicated below. The register is then placed between the TDI and TDO pins when the controller is moved into Shift-DR state. Bit 0 in the register is the LSB and the first to reach TDO when shifting begins.

ID Register Contents

		Revi	ie sion de						!	Not !	Used	i					I/O GSI Technology JEDEC Vendor ID Code							Presence Register								
Bit #	31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
x36	Х	Χ	Х	Χ	0	0	0	Х	1	0	0	1	0	0	0	0	1	0	0	0	0	0	0	1	1	0	1	1	0	0	1	1
x18	Х	Χ	Χ	Χ	0	0	0	Х	1	0	0	1	0	0	0	0	1	0	1	0	0	0	0	1	1	0	1	1	0	0	1	1



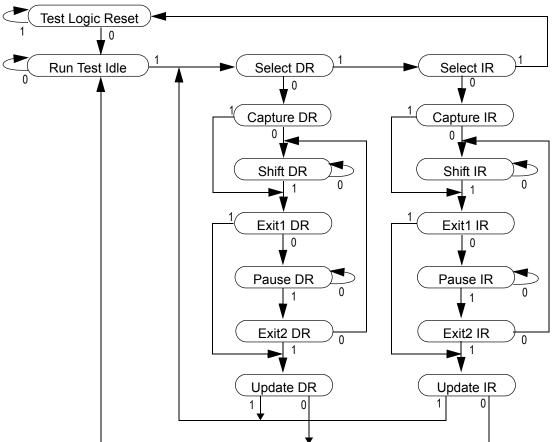
Tap Controller Instruction Set

Overview

There are two classes of instructions defined in the Standard 1149.1-1990; the standard (Public) instructions, and device specific (Private) instructions. Some Public instructions are mandatory for 1149.1 compliance. Optional Public instructions must be implemented in prescribed ways. The TAP on this device may be used to monitor all input and I/O pads, and can be used to load address, data or control signals into the RAM or to preload the I/O buffers.

When the TAP controller is placed in Capture-IR state the two least significant bits of the instruction register are loaded with 01. When the controller is moved to the Shift-IR state the Instruction Register is placed between TDI and TDO. In this state the desired instruction is serially loaded through the TDI input (while the previous contents are shifted out at TDO). For all instructions, the TAP executes newly loaded instructions only when the controller is moved to Update-IR state. The TAP instruction set for this device is listed in the following table.

JTAG Tap Controller State Diagram



Instruction Descriptions

BYPASS

When the BYPASS instruction is loaded in the Instruction Register the Bypass Register is placed between TDI and TDO. This occurs when the TAP controller is moved to the Shift-DR state. This allows the board level scan path to be shortened to facilitate testing of other devices in the scan path.





SAMPLE/PRELOAD

SAMPLE/PRELOAD is a Standard 1149.1 mandatory public instruction. When the SAMPLE / PRELOAD instruction is loaded in the Instruction Register, moving the TAP controller into the Capture-DR state loads the data in the RAMs input and I/O buffers into the Boundary Scan Register. Boundary Scan Register locations are not associated with an input or I/O pin, and are loaded with the default state identified in the Boundary Scan Chain table at the end of this section of the datasheet. Because the RAM clock is independent from the TAP Clock (TCK) it is possible for the TAP to attempt to capture the I/O ring contents while the input buffers are in transition (i.e. in a metastable state). Although allowing the TAP to sample metastable inputs will not harm the device, repeatable results cannot be expected. RAM input signals must be stabilized for long enough to meet the TAPs input data capture set-up plus hold time (tTS plus tTH). The RAMs clock inputs need not be paused for any other TAP operation except capturing the I/O ring contents into the Boundary Scan Register. Moving the controller to Shift-DR state then places the boundary scan register between the TDI and TDO pins.

EXTEST

EXTEST is an IEEE 1149.1 mandatory public instruction. It is to be executed whenever the instruction register is loaded with all logic 0s. The EXTEST command does not block or override the RAM's input pins; therefore, the RAM's internal state is still determined by its input pins.

Typically, the Boundary Scan Register is loaded with the desired pattern of data with the SAMPLE/PRELOAD command. Then the EXTEST command is used to output the Boundary Scan Register's contents, in parallel, on the RAM's data output drivers on the falling edge of TCK when the controller is in the Update-IR state.

Alternately, the Boundary Scan Register may be loaded in parallel using the EXTEST command. When the EXTEST instruction is selected, the sate of all the RAM's input and I/O pins, as well as the default values at Scan Register locations not associated with a pin, are transferred in parallel into the Boundary Scan Register on the rising edge of TCK in the Capture-DR state, the RAM's output pins drive out the value of the Boundary Scan Register location with which each output pin is associated.

IDCODE

The IDCODE instruction causes the ID ROM to be loaded into the ID register when the controller is in Capture-DR mode and places the ID register between the TDI and TDO pins in Shift-DR mode. The IDCODE instruction is the default instruction loaded in at power up and any time the controller is placed in the Test-Logic-Reset state.

SAMPLE-Z

If the SAMPLE-Z instruction is loaded in the instruction register, all RAM outputs are forced to an inactive drive state (high-Z) and the Boundary Scan Register is connected between TDI and TDO when the TAP controller is moved to the Shift-DR state.

RFU

These instructions are Reserved for Future Use. In this device they replicate the BYPASS instruction.



JTAG TAP Instruction Set Summary

Instruction	Code	Description	Notes
EXTEST	000	Places the Boundary Scan Register between TDI and TDO.	1
IDCODE	001	Preloads ID Register and places it between TDI and TDO.	1, 2
SAMPLE-Z	010	Captures I/O ring contents. Places the Boundary Scan Register between TDI and TDO. Forces all RAM output drivers to High-Z.	1
RFU	011	Do not use this instruction; Reserved for Future Use. Replicates BYPASS instruction. Places Bypass Register between TDI and TDO.	1
SAMPLE/ PRELOAD	100	Captures I/O ring contents. Places the Boundary Scan Register between TDI and TDO.	1
GSI	101	GSI private instruction.	1
RFU	110	Do not use this instruction; Reserved for Future Use. Replicates BYPASS instruction. Places Bypass Register between TDI and TDO.	1
BYPASS	111	Places Bypass Register between TDI and TDO.	1

- 1. Instruction codes expressed in binary, MSB on left, LSB on right.
- 2. Default instruction automatically loaded at power-up and in test-logic-reset state.



JTAG Port Recommended Operating Conditions and DC Characteristics

Parameter	Symbol	Min.	Max.	Unit	Notes
3.3 V Test Port Input High Voltage	V _{IHJ3}	2.0	V _{DD3} +0.3	V	1
3.3 V Test Port Input Low Voltage	V _{ILJ3}	-0.3	0.8	V	1
2.5 V Test Port Input High Voltage	V _{IHJ2}	0.6 * V _{DD2}	V _{DD2} +0.3	V	1
2.5 V Test Port Input Low Voltage	V _{ILJ2}	-0.3	0.3 * V _{DD2}	V	1
TMS, TCK and TDI Input Leakage Current	I _{INHJ}	-300	1	uA	2
TMS, TCK and TDI Input Leakage Current	I _{INLJ}	– 1	100	uA	3
TDO Output Leakage Current	I _{OLJ}	- 1	1	uA	4
Test Port Output High Voltage	V _{OHJ}	1.7	_	V	5, 6
Test Port Output Low Voltage	V _{OLJ}	_	0.4	V	5, 7
Test Port Output CMOS High	V _{OHJC}	V _{DDQ} – 100 mV	_	V	5, 8
Test Port Output CMOS Low	V _{OLJC}	_	100 mV	V	5, 9

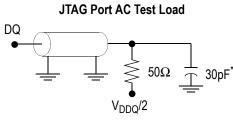
Notes:

- 1. Input Under/overshoot voltage must be -2 V > Vi < V_{DDn} +2 V not to exceed 4.6 V maximum, with a pulse width not to exceed 20% tTKC.
- 2. $V_{ILJ} \le V_{IN} \le V_{DDn}$
- $3. \quad 0 \ V \leq V_{IN} \leq V_{ILJn}$
- 4. Output Disable, $V_{OUT} = 0$ to V_{DDn}
- 5. The TDO output driver is served by the $V_{\mbox{\scriptsize DDQ}}$ supply.
- 6. $I_{OH,I} = -4 \text{ mA}$
- 7. $I_{OLJ} = + 4 \text{ mA}$
- 8. $I_{OHJC} = -100 \text{ uA}$
- 9. $I_{OLJC} = +100 \text{ uA}$

JTAG Port AC Test Conditions

Parameter	Conditions
Input high level	V _{DD} – 0.2 V
Input low level	0.2 V
Input slew rate	1 V/ns
Input reference level	V _{DDQ} /2
Output reference level	V _{DDQ} /2

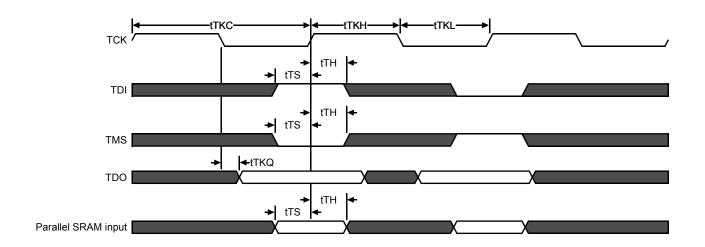
- 1. Include scope and jig capacitance.
- Test conditions as shown unless otherwise noted.



* Distributed Test Jig Capacitance



JTAG Port Timing Diagram



JTAG Port AC Electrical Characteristics

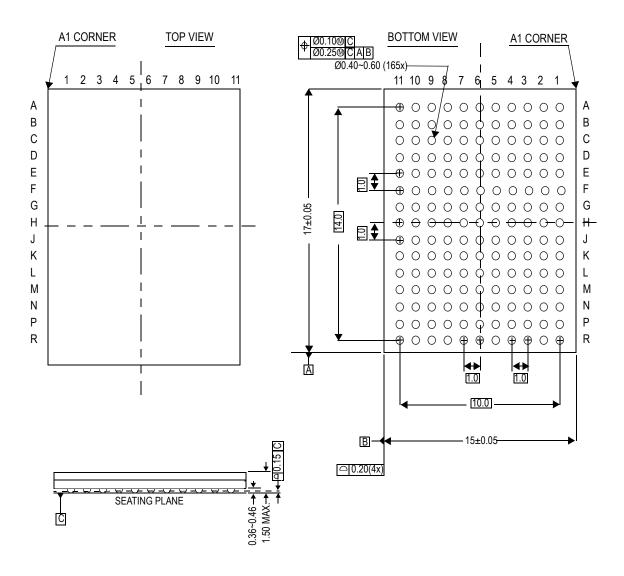
Parameter	Symbol	Min	Max	Unit
TCK Cycle Time	tTKC	50	_	ns
TCK Low to TDO Valid	tTKQ	_	20	ns
TCK High Pulse Width	tTKH	20	_	ns
TCK Low Pulse Width	tTKL	20	_	ns
TDI & TMS Set Up Time	tTS	10	_	ns
TDI & TMS Hold Time	tTH	10	_	ns

Boundary Scan (BSDL Files)

For information regarding the Boundary Scan Chain, or to obtain BSDL files for this part, please contact our Applications Engineering Department at: apps@gsitechnology.com.



Package Dimensions—165-Bump FPBGA (Package E)





Ordering Information for GSI Synchronous Burst RAMs

Org	Part Number ¹	Туре	Package	Speed ² (MHz/ns)	T _A ³	Status
2M x 18	GS832118E-250	Pipeline/Flow Through	165 BGA	250/5.5	С	
2M x 18	GS832118E-225	Pipeline/Flow Through	165 BGA	225/6	С	
2M x 18	GS832118E-200	Pipeline/Flow Through	165 BGA	200/6.5	С	
2M x 18	GS832118E-166	Pipeline/Flow Through	165 BGA	166/7	С	
2M x 18	GS832118E-150	Pipeline/Flow Through	165 BGA	150/7.5	С	
2M x 18	GS832118E-133	Pipeline/Flow Through	165 BGA	133/8.5	С	
1M x 32	GS832132E-250	Pipeline/Flow Through	165 BGA	250/5.5	С	
1M x 32	GS832132E-225	Pipeline/Flow Through	165 BGA	225/6	С	
1M x 32	GS832132E-200	Pipeline/Flow Through	165 BGA	200/6.5	С	
1M x 32	GS832132E-166	Pipeline/Flow Through	165 BGA	166/7	С	
1M x 32	GS832132E-150	Pipeline/Flow Through	165 BGA	150/7.5	С	
1M x 32	GS832132E-133	Pipeline/Flow Through	165 BGA	133/8.5	С	
1M x 36	GS832136E-250	Pipeline/Flow Through	165 BGA	250/5.5	С	
1M x 36	GS832136E-225	Pipeline/Flow Through	165 BGA	225/6	С	
1M x 36	GS832136E-200	Pipeline/Flow Through	165 BGA	200/6.5	С	
1M x 36	GS832136E-166	Pipeline/Flow Through	165 BGA	166/7	С	
1M x 36	GS832136E-150	Pipeline/Flow Through	165 BGA	150/7.5	С	
1M x 36	GS832136E-133	Pipeline/Flow Through	165 BGA	133/8.5	С	
2M x 18	GS832118E-250I	Pipeline/Flow Through	165 BGA	250/5.5	I	
2M x 18	GS832118E-225I	Pipeline/Flow Through	165 BGA	225/6	I	
2M x 18	GS832118E-200I	Pipeline/Flow Through	165 BGA	200/6.5	I	
2M x 18	GS832118E-166I	Pipeline/Flow Through	165 BGA	166/7	I	
2M x 18	GS832118E-150I	Pipeline/Flow Through	165 BGA	150/7.5	I	

- Customers requiring delivery in Tape and Reel should add the character "T" to the end of the part number. Example: GS832118E-166IT.
- The speed column indicates the cycle frequency (MHz) of the device in Pipeline mode and the latency (ns) in Flow Through mode. Each device is Pipeline/Flow Through mode-selectable by the user.
- 3. $T_A = C = Commercial Temperature Range. T_A = I = Industrial Temperature Range.$
- 4. GSI offers other versions this type of device in many different configurations and with a variety of different features, only some of which are covered in this data sheet. See the GSI Technology web site (www.gsitechnology.com) for a complete listing of current offerings.



Ordering Information for GSI Synchronous Burst RAMs

Org	Part Number ¹	Туре	Package	Speed ² (MHz/ns)	T _A ³	Status
2M x 18	GS832118E-133I	Pipeline/Flow Through	165 BGA	133/8.5	I	
1M x 32	GS832132E-250I	Pipeline/Flow Through	165 BGA	250/5.5	I	
1M x 32	GS832132E-225I	Pipeline/Flow Through	165 BGA	225/6	I	
1M x 32	GS832132E-200I	Pipeline/Flow Through	165 BGA	200/6.5	I	
1M x 32	GS832132E-166I	Pipeline/Flow Through	165 BGA	166/7	I	
1M x 32	GS832132E-150I	Pipeline/Flow Through	165 BGA	150/7.5	I	
1M x 32	GS832132E-133I	Pipeline/Flow Through	165 BGA	133/8.5	I	
1M x 36	GS832136E-250I	Pipeline/Flow Through	165 BGA	250/5.5	1	
1M x 36	GS832136E-225I	Pipeline/Flow Through	165 BGA	225/6	I	
1M x 36	GS832136E-200I	Pipeline/Flow Through	165 BGA	200/6.5	I	
1M x 36	GS832136E-166I	Pipeline/Flow Through	165 BGA	166/7	I	
1M x 36	GS832136E-150I	Pipeline/Flow Through	165 BGA	150/7.5	I	
1M x 36	GS832136E-133I	Pipeline/Flow Through	165 BGA	133/8.5	I	
2M x 18	GS832118GE-250	Pipeline/Flow Through	RoHS-compliant 165 BGA	250/5.5	С	
2M x 18	GS832118GE-225	Pipeline/Flow Through	RoHS-compliant 165 BGA	225/6	С	
2M x 18	GS832118GE-200	Pipeline/Flow Through	RoHS-compliant 165 BGA	200/6.5	С	
2M x 18	GS832118GE-166	Pipeline/Flow Through	RoHS-compliant 165 BGA	166/7	С	
2M x 18	GS832118GE-150	Pipeline/Flow Through	RoHS-compliant 165 BGA	150/7.5	С	
2M x 18	GS832118GE-133	Pipeline/Flow Through	RoHS-compliant 165 BGA	133/8.5	С	
1M x 32	GS832132GE-250	Pipeline/Flow Through	RoHS-compliant 165 BGA	250/5.5	С	
1M x 32	GS832132GE-225	Pipeline/Flow Through	RoHS-compliant 165 BGA	225/6	С	
1M x 32	GS832132GE-200	Pipeline/Flow Through	RoHS-compliant 165 BGA	200/6.5	С	
1M x 32	GS832132GE-166	Pipeline/Flow Through	RoHS-compliant 165 BGA	166/7	С	
1M x 32	GS832132GE-150	Pipeline/Flow Through	RoHS-compliant 165 BGA	150/7.5	С	
1M x 32	GS832132GE-133	Pipeline/Flow Through	RoHS-compliant 165 BGA	133/8.5	С	

Notes:

- 1. Customers requiring delivery in Tape and Reel should add the character "T" to the end of the part number. Example: GS832118E-166IT.
- 2. The speed column indicates the cycle frequency (MHz) of the device in Pipeline mode and the latency (ns) in Flow Through mode. Each device is Pipeline/Flow Through mode-selectable by the user.
- 3. $T_A = C = Commercial Temperature Range. T_A = I = Industrial Temperature Range.$
- 4. GSI offers other versions this type of device in many different configurations and with a variety of different features, only some of which are covered in this data sheet. See the GSI Technology web site (www.gsitechnology.com) for a complete listing of current offerings.

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Ordering Information for GSI Synchronous Burst RAMs

Org	Part Number ¹	Туре	Package	Speed ² (MHz/ns)	T _A ³	Status
1M x 36	GS832136GE-250	Pipeline/Flow Through	RoHS-compliant 165 BGA	250/5.5	С	
1M x 36	GS832136GE-225	Pipeline/Flow Through	RoHS-compliant 165 BGA	225/6	С	
1M x 36	GS832136GE-200	Pipeline/Flow Through	RoHS-compliant 165 BGA	200/6.5	С	
1M x 36	GS832136GE-166	Pipeline/Flow Through	RoHS-compliant 165 BGA	166/7	С	
1M x 36	GS832136GE-150	Pipeline/Flow Through	RoHS-compliant 165 BGA	150/7.5	С	
1M x 36	GS832136GE-133	Pipeline/Flow Through	RoHS-compliant 165 BGA	133/8.5	С	
2M x 18	GS832118GE-250I	Pipeline/Flow Through	RoHS-compliant 165 BGA	250/5.5	I	
2M x 18	GS832118GE-225I	Pipeline/Flow Through	RoHS-compliant 165 BGA	225/6	I	
2M x 18	GS832118GE-200I	Pipeline/Flow Through	RoHS-compliant 165 BGA	200/6.5	I	
2M x 18	GS832118GE-166I	Pipeline/Flow Through	RoHS-compliant 165 BGA	166/7	I	
2M x 18	GS832118GE-150I	Pipeline/Flow Through	RoHS-compliant 165 BGA	150/7.5	I	
2M x 18	GS832118GE-133I	Pipeline/Flow Through	RoHS-compliant 165 BGA	133/8.5	I	
1M x 32	GS832132GE-250I	Pipeline/Flow Through	RoHS-compliant 165 BGA	250/5.5	I	
1M x 32	GS832132GE-225I	Pipeline/Flow Through	RoHS-compliant 165 BGA	225/6	I	
1M x 32	GS832132GE-200I	Pipeline/Flow Through	RoHS-compliant 165 BGA	200/6.5	I	
1M x 32	GS832132GE-166I	Pipeline/Flow Through	RoHS-compliant 165 BGA	166/7	I	
1M x 32	GS832132GE-150I	Pipeline/Flow Through	RoHS-compliant 165 BGA	150/7.5	I	
1M x 32	GS832132GE-133I	Pipeline/Flow Through	RoHS-compliant 165 BGA	133/8.5	I	
1M x 36	GS832136GE-250I	Pipeline/Flow Through	RoHS-compliant 165 BGA	250/5.5	I	
1M x 36	GS832136GE-225I	Pipeline/Flow Through	RoHS-compliant 165 BGA	225/6	I	
1M x 36	GS832136GE-200I	Pipeline/Flow Through	RoHS-compliant 165 BGA	200/6.5	I	
1M x 36	GS832136GE-166I	Pipeline/Flow Through	RoHS-compliant 165 BGA	166/7	I	
1M x 36	GS832136GE-150I	Pipeline/Flow Through	RoHS-compliant 165 BGA	150/7.5	I	
1M x 36	GS832136GE-133I	Pipeline/Flow Through	RoHS-compliant 165 BGA	133/8.5	I	

- 1. Customers requiring delivery in Tape and Reel should add the character "T" to the end of the part number. Example: GS832118E-166IT.
- 2. The speed column indicates the cycle frequency (MHz) of the device in Pipeline mode and the latency (ns) in Flow Through mode. Each device is Pipeline/Flow Through mode-selectable by the user.
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36Mb Sync SRAM Datasheet Revision History

DS/DateRev. Code: Old; New	Types of Changes Format or Content	Page:Revisions:Reason	
8321xx_r1		Creation of new datasheet	
8321xx_r1; 8321xx_r1_01	Content	 Added parity bit designators to x18 and x36 pinouts Removed address pin numbers (except 0 and 1) Corrected "E" package mechanical drawing thickness to 1.4 mm 	
8321xx_r1_01; 8321xx_r1_02	Format/Content	Updated format Added variation information to package mechanical	
8321xx_r1_02; 8321xx_r1_03	Content	RoHS-compliant information added	
8321xx_r1_03; 8321xx_r1_04	Content	Updated Truth Tables (pg. 8, 9)	
8321xx_r1_04; 8321xx_r1_05	Content	Removed Preliminary banner due to production status Updated mechanical drawing	